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1200V, 85A, $V_{ce(on)}$ = 2.5V Typical

Ultra Fast NPT - IGBT®

The Ultra Fast NPT - IGBT® family of products is the newest generation of planar IGBTs optimized for outstanding ruggedness and the best trade-off between conduction and switching losses.

Features

- · Low Saturation Voltage
- Low Tail Current
- RoHS Compliant

- Short Circuit Withstand Rated
- High Frequency Switching
- Ultra Low Leakage Current



ISOTOP® Combi (IGBT and Diode)



Unless stated otherwise, Microsemi discrete IGBTs contain a single IGBT die. This device is recommended for applications such as induction heating (IH), motor control, general purpose inverters and uninterruptible power supplies (UPS).

MAXIMUM RATINGS

MAXIMUM RATINGS		All Ratings: $T_C = 25^{\circ}C$ unless otherwise specified			
Symbol	Parameter	Ratings	Unit		
V _{ces}	Collector Emitter Voltage	1200	V		
$V_{\rm GE}$	Gate-Emitter Voltage	±30	V		
I _{C1}	Continuous Collector Current @ T _C = 25°C	118			
I _{C2}	Continuous Collector Current @ T _c = 75°C	85	Α		
I _{CM}	Pulsed Collector Current ①	340			
SCWT	Short Circuit Withstand Time: V _{CE} = 600V, V _{GE} = 15V, T _C =125°C	10	μs		
$P_{_{\mathrm{D}}}$	Total Power Dissipation @ T _c = 25°C	595	W		
T _J ,T _{STG}	Operating and Storage Junction Temperature Range	-55 to 150	°C		
T _L	Max. Lead Temp. for Soldering: 0.063" from Case for 10 Sec.	300			

STATIC ELECTRICAL CHARACTERISTICS

Symbol	Parameter	Min	Тур	Max	Unit
V _{(BR)CES}	Collector-Emitter Breakdown Voltage (V _{GE} = 0V, I _C = 1.0mA)	1200			
V _{GE(TH)}	Gate Threshold Voltage $(V_{CE} = V_{GE}, I_{C} = 2.5 \text{mA}, T_{j} = 25 ^{\circ}\text{C})$	3.5	5.0	6.5	Volts
V _{CE(ON)}	Collector-Emitter On Voltage (V _{GE} = 15V, I _C = 85A, T _j = 25°C)		2.5	3.2	
	Collector-Emitter On Voltage ($V_{GE} = 15V$, $I_{C} = 85A$, $T_{j} = 125^{\circ}C$)		3.3		
	Collector-Emitter On Voltage ($V_{GE} = 15V$, $I_{C} = 170A$, $T_{j} = 25^{\circ}C$)		3.5		
I _{CES}	Collector Cut-off Current (V _{CE} = 1200V, V _{GE} = 0V, T _j = 25°C) ②		20	1100	μA
	Collector Cut-off Current (V _{CE} = 1200V, V _{GE} = 0V, T _j = 125°C) ②		200		
I _{GES}	Gate-Emitter Leakage Current (V _{GE} = ±20V)			±250	nA

CAUTION: These Devices are Sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed.

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
C _{ies}	Input Capacitance	Capacitance		8400		
C _{oes}	Output Capacitance	$V_{GE} = 0V, V_{CE} = 25V$		725		pF
C _{res}	Reverse Transfer Capacitance	f = 1MHz		190		
V_{GEP}	Gate to Emitter Plateau Voltage	Cata Charga		7.5		V
Qg3	Total Gate Charge	Gate Charge		490	660	
Q _{ge}	Gate-Emitter Charge	V _{GE} = 15V		60	85	 0
Q_{gc}	Gate- Collector Charge	$V_{CE} = 600V$ $I_{C} = 85A$		230	320	nC
t _{d(on)}	Turn-On Delay Time	Inductive Switching (25°C)		43		
t,	Current Rise Time	V _{CC} = 600V		70		20
t _{d(off)}	Turn-Off Delay Time	V _{GE} = 15V		300		ns
t _f	Current Fall Time	I _C = 85A		85		
E _{on2} 5	Turn-On Switching Energy	$R_{_{\rm G}} = 4.3 \ \Omega^{\textcircled{4}}$		6000	9000	1
E _{off}	Turn-Off Switching Energy	T _J = +25°C		3800	5700	μJ
t _{d(on)}	Turn-On Delay Time	Inductive Switching (125°C)		43		
t,	Current Rise Time	V _{CC} = 600V		70		20
t _{d(off)}	Turn-Off Delay Time	V _{GE} = 15V		350		ns
t _f	Current Fall Time	I _C = 85A		95		
E _{on2} 5	Turn-On Switching Energy	$R_{_{\rm G}} = 4.3 \ \Omega^{\textcircled{4}}$		7800	11,700	1
E _{off}	Turn-Off Switching Energy	T _J = +125°C		4900	7350	μJ

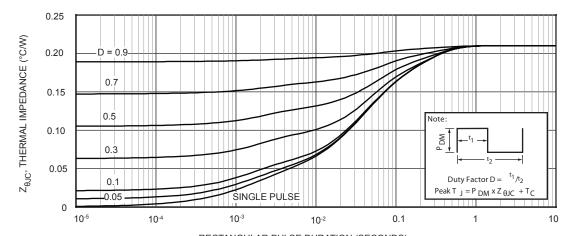
THERMAL AND MECHANICAL CHARACTERISTICS

Symbol	Characteristic / Test Conditions	Min	Тур	Max	Unit
$R_{\theta JC}$	Junction to Case Thermal Resistance (IGBT)	-	-	0.21	°C/M/
$R_{\theta JC}$	Junction to Case Thermal Resistance (Diode)	-	-	0.56	°C/W
W _T	Package Weight	-	1.03	-	OZ
Та наа	orque Terminals and Mounting Screws.	-	-	10	in·lbf
iorque		-	-	1.1	N·m
V _{Isolation}	RMS Voltage (50-60Hz Sinusoidal Waveform from Terminals to Mounting Base for 1 Min.)	2500	-	-	Volts

- 1 Repetitive Rating: Pulse width and case temperature limited by maximum junction temperature.
- 2 Pulse test: Pulse Width < $380\mu s$, duty cycle < 2%.
- 3 See Mil-Std-750 Method 3471.
- 4 R_s is external gate resistance, not including internal gate resistance or gate driver impedance. (MIC4452)
- 5 E_{on2} is the energy loss at turn-on and includes the charge stored in the freewheeling diode.

6 E_{off} is the clamped inductive turn-off energy measured in accordance with JEDEC standard JESD24-1.

Microsemi reserves the right to change, without notice, the specifications and information contained herein.



RECTANGULAR PULSE DURATION (SECONDS)
Figure 1, Maximum Effective Transient Thermal Impedance, Junction-To-Case vs Pulse Duration

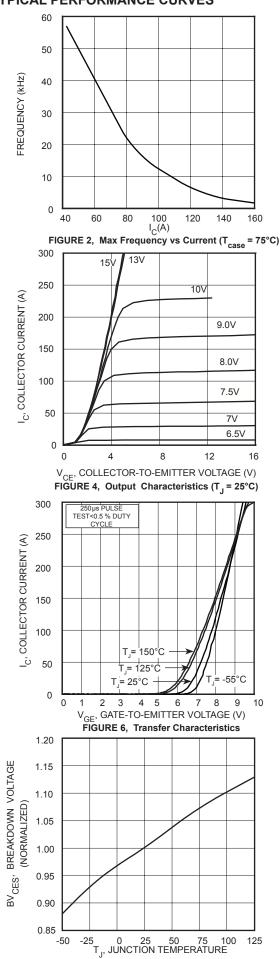


FIGURE 8, Breakdown Voltage vs Junction Temperature

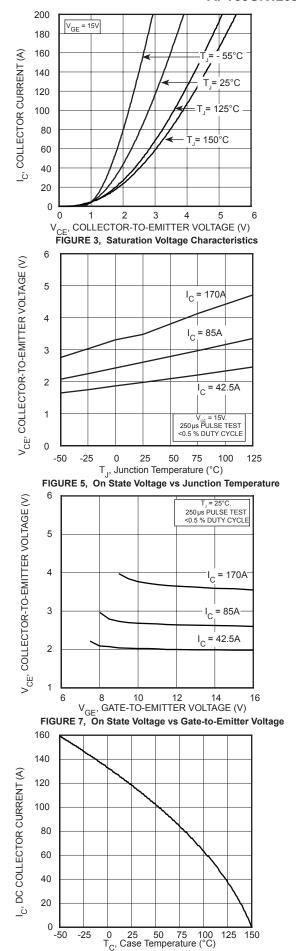
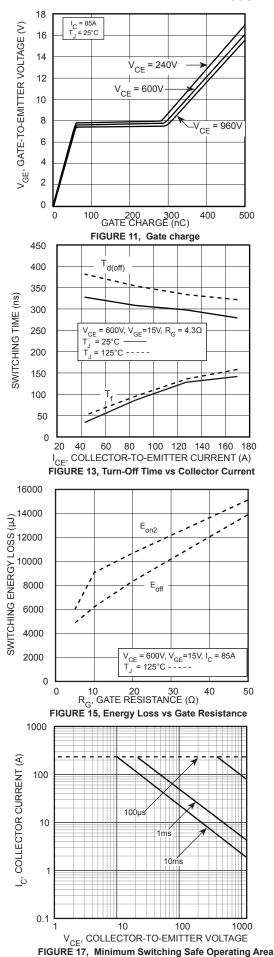


FIGURE 9, DC Collector Current vs Case Temperature



ULTRAFAST SOFT RECOVERY RECTIFIER DIODE

All Ratings: $T_C = 25$ °C unless otherwise specified. **MAXIMUM RATINGS**

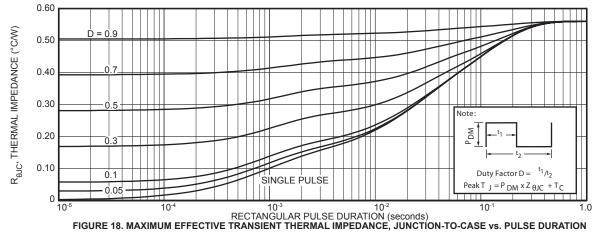
Symbol	Characteristic / Test Conditions	APT85GR120JD60	Unit
I _{F(AV)}	Maximum Average Forward Current (T _C = 92°C, Duty Cycle = 0.5)	60	
I _{F(RMS)}	RMS Forward Current (Square wave, 50% duty)	73	Amps
I _{FSM}	Non-Repetitive Forward Surge Current (T _J = 45°C, 8.3 ms)	540	

STATIC ELECTRICAL CHARACTERISTICS

Symbol	Characteristic / Test Conditions		Min	Туре	Max	Unit
		I _F = 60A		2.5		
V_{F}	Forward Voltage	I _F = 120A		3.07		Volts
		I _F = 60A, T _J = 125°C		1.82		

DYNAMIC CHARACTERISTICS

Symbol	Characteristic	Test Conditions	Min	Тур	Max	Unit
t _{rr}	Reverse Recovery Time	$I_F = 1A$, $di_F/dt = -100A/\mu s$, $V_R = 30V$, $T_J = 25$ °C	-	60	-	ns
t _{rr}	Reverse Recovery Time	$I_F = 60A$, $di_F/dt = -200A/\mu s$ $V_R = 800V$, $T_C = 25^{\circ}C$	-	265	-	
Q_{rr}	Reverse Recovery Charge		-	560	-	nC
I _{RRM}	Maximum Reverse Recovery Current		-	5	-	Amps
t _{rr}	Reverse Recovery Time		-	350	-	ns
Q_{rr}	Reverse Recovery Charge	$I_F = 60A$, $di_F/dt = -200A/\mu s$ $V_R = 800V$, $T_C = 125^{\circ}C$	-	2890	-	nC
I _{RRM}	Maximum Reverse Recovery Current		-	13	-	Amps
t _{rr}	Reverse Recovery Time	$I_F = 60A$, $di_F/dt = -1000A/\mu s$ $V_R = 800V$, $T_C = 125°C$	-	150	-	ns
Q _{rr}	Reverse Recovery Charge		-	4720	-	nC
I _{RRM}	Maximum Reverse Recovery Current		-	40	-	Amps



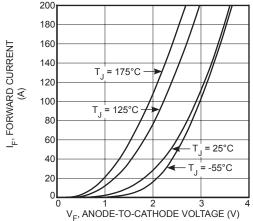


Figure 19. Forward Current vs. Forward Voltage

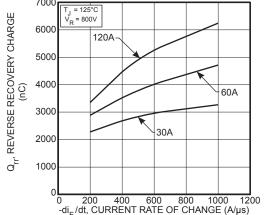


Figure 21. Reverse Recovery Charge vs. Current Rate of Change

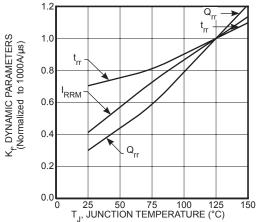
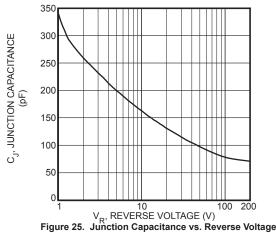


Figure 23. Dynamic Parameters vs. Junction Temperature



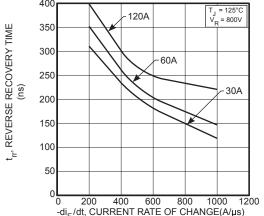


Figure 20. Reverse Recovery Time vs. Current Rate of Change

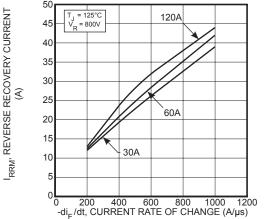


Figure 22. Reverse Recovery Current vs. Current Rate of Change

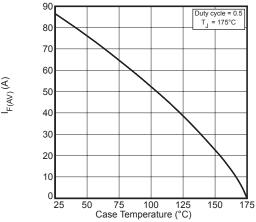


Figure 24. Maximum Average Forward Current vs. CaseTemperature

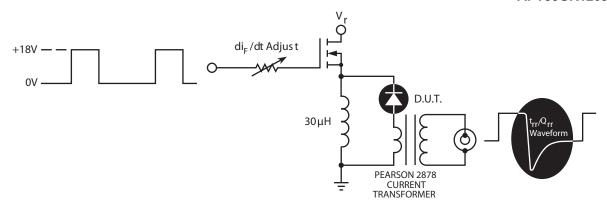
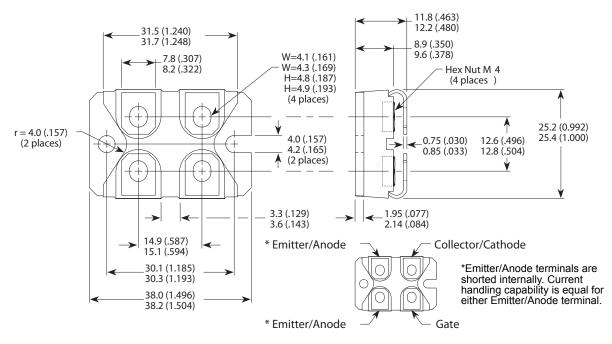


Figure 26. Diode Test Circuit

1 I_F - Forward Conduction Current
 2 di_F/dt - Rate of Diode Current Change Through Zero Crossing.
 3 I_{RRM} - Maximum Reverse Recovery Current
 4 t_{rr} - Reverse Recovery Time measured from zero crossing where diode current goes from positive to negative, to the point at which the straight line through I_{RRM} and 0.25, I_{RRM} passes through zero.
 5 Q_{rr} - Area Under the Curve Defined by I_{RRM} and t_{RR}.

Figure 27. Diode Reverse Recovery Waveform Definition

SOT-227 (ISOTOP®) Package Outline



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